



FORM PTO-1449 (MODIFIED)

INFORMATION DISCLOSURE STATEMENT
(Use several sheets if necessary)

	ATTY. DOCKET NO.: 02008.071003	SERIAL NO.: 10/779,904
APPLICANT: Masahiro ISHIDA et al.		
FILING DATE: 02/17/2004	ART UNIT: 2136 OAL	

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	REF	DOCUMENT NO.	DATE	APPLICANT'S OR PATENTEE'S NAME
/OAL/	A1	5,790,565	08/04/1998	Sakaguchi

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	REF	DOCUMENT NO.	DATE	COUNTRY	TRANSLATION	
					YES	NO
/OAL/	A2	DE 196 26 103 A1	01/02/1997	Germany		X
/OAL/	A3	DE 196 09 085 A1	09/12/1996	Germany		X
/OAL/	A4	10 - 239394	09/11/1998	Japan		X
/OAL/	A5	8 - 201486	08/09/1996	Japan		X

OTHER DOCUMENTS

EXAMINER INITIALS	REF	(Include Author, Title, Date, Pertinent Pages, etc.)
/OAL/	A6	German Office Action dated 01/23/2004 (7 pgs.)
/OAL/	A7	Patent Abstracts of Japan, Publication No. 10239394A dated 09/11/1998, 1 pg.
/OAL/	A8	Patent Abstracts of Japan, Publication No. 08201486A dated 08/09/1996, 1 pg.

EXAMINER: /Oscar Louie/ (08/21/2007)	DATE CONSIDERED: 08/21/2007
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	



PTO/SB/08a/b (07-05)

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Substitute for form 1449A/B/PTO

Complete If Known

INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>				Application Number	10/779,904-Conf. #9608
Sheet	1	of	2	Filing Date	February 17, 2004
				First Named Inventor	Masahiro Ishida
				Art Unit	2435 Z 136 OAL
				Examiner Name	Not Yet Assigned Oscar Louie
				Attorney Docket Number	02008/071003

OAL

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ³
		Country Code ⁴ -Number ⁴ -Kind Code ⁵ (if known)				
/OAL	BA	JP-4-244975	09-01-1992	Matsushita Electron Corp		
	BB	JP-6-258388	09-16-1994	Hitachi Ltd		
	BC	JP-8-201486	08-09-1996	Nec Corp		
	BD	JP-9-26981	01-28-1997	Fujitsu Ltd		
	BE	JP-9-54140	02-25-1997	Sharp Corp		
	BF	JP-9-80114	03-28-1997	Advantest Corp		
	BG	JP-10-125794	05-15-1998	NEC Corp		
	BH	JP-10-239394	09-11-1998	NEC Corp		
↓	BI	JP-11-174114	07-02-1999	Toshiba Corp		
	BJ	JP-60-165562	08-28-1985	Vladimirsky et al.		
/OAL	BK	JP-62-39780	02-20-1987	Mitsubishi Electric Corporation		

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NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
/OAL	CA	Patent Abstracts of Japan; Publication number: 04-244975; Date of Publication: 09/01/1992 (2 pages)	
	CB	Patent Abstracts of Japan; Publication number: 06-258388; Date of Publication: 09/16/1994 (2 pages)	
	CC	Patent Abstracts of Japan; Publication number: 08-201486; Date of Publication: 08/09/1996 (2 pages)	
	CD	Patent Abstracts of Japan; Publication number: 09-026981; Date of Publication: 01/28/1997 (2 pages)	
	CE	Patent Abstracts of Japan; Publication number: 09-054140; Date of Publication: 02/25/1997 (2 pages)	
	CF	Patent Abstracts of Japan; Publication number: 09-080114; Date of Publication: 03/28/1997 (2 pages)	
	CG	Patent Abstracts of Japan; Publication number: 10-125794; Date of Publication: 05/15/1998 (2 pages)	
↓	CH	Patent Abstracts of Japan; Publication number: 10-239394; Date of Publication: 09/11/1998 (2 pages)	
/OAL	CI	Patent Abstracts of Japan; Publication number: 11-174114; Date of Publication: 07/02/1999 (2 pages)	

Examiner Signature	/Oscar Louie/ (08/21/2007)	Date Considered	08/21/2007
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Substitute for form 1449A/B/PTO				Complete If Known	
				Application Number	10/779,904-Conf. #9608
				Filing Date	February 17, 2004
				First Named Inventor	Masahiro Ishida
				Art Unit	2133
				Examiner Name	Not Yet Assigned
Sheet	2	of	2	Attorney Docket Number	02008/071003

		pages)	
/OAL/	CJ	Patent Abstracts of Japan; Publication number: 11-174114; Date of Publication: 07/02/1999 (2 pages)	
/OAL/	CK	"Transient Power Supply Current Testing of Digital CMOS Circuits"; Rafic Z. Makki et al.; International Test Conference; Paper 38.1; IEEE; 1995; pp. 892-901	
/OAL/	CL	"Defect Detection with Transient Current Testing and its Potential for Deep Sub-micron CMOS ICs"; Manoj Sachdev et al; International Test Conference; IEEE 1998; Paper 8.4; pp. 204-213	
/OAI/	CM	Translation of Japanese Office Action dated April 4, 2006 (2 pages)	

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